

Description

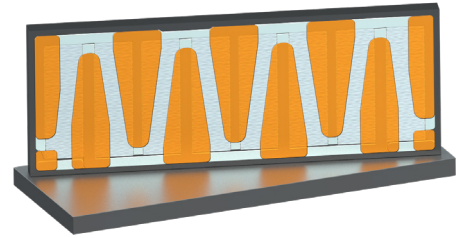
- GaN enhancement mode power switch die
- $R_{DS(on)} = 7 \text{ m}\Omega$
- Ultra-low FOM Island Technology™ die
- Easy gate drive requirements (0 V to 6 V)
- Fast and controllable fall and rise times
- Reverse current capability
- Dual gate pads for optimal module layout
- Zero reverse recovery loss

Applications

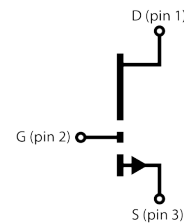
- DC-DC Power Stages

Key Parameters

Parameter	Value	Unit
V_{DS}	100	V
I_D	90	A
Die Size	5.47 x 2.05	mm x mm
Die Thickness	265	μm



Circuit Symbol



The die substrate should be connected to the source pad for optimal performance.

Absolute Maximum Ratings ($T_{case} = 25 \text{ }^\circ\text{C}$ except as noted)

Parameter	Symbol	Value	Unit
Operating Junction Temperature	T_S	-55 to +150	$^\circ\text{C}$
Storage Temperature Range	T_J	-55 to +150	$^\circ\text{C}$
Drain-to-Source Voltage	V_{DS}	100	V
Drain to Source Voltage - transient (note 1)	$V_{DS(transient)}$	130	V
Gate-to-Source Voltage	V_{GS}	-10 to +7	V
Gate-to-Source Voltage - transient (note 1)	$V_{GS(transient)}$	-20 to + 10	V
Continuous Drain Current ($T_{case}=25 \text{ }^\circ\text{C}$) (note 2)	I_{DS}	90	A
Continuous Drain Current ($T_{case}=100 \text{ }^\circ\text{C}$) (note 2)	I_{DS}	65	A

(1) For 1 μs

(2) Limited by saturation

Thermal Characteristics (Typical values unless otherwise noted)

Parameter	Symbol	Value	Unit
Thermal Resistance (junction-to-substrate)	$R_{\theta J-SUB}$	0.38	$^\circ\text{C/W}$
Thermal Resistance (junction-to-top side RDL)	$R_{\theta J-RDL}$	0.70	$^\circ\text{C/W}$

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Mechanical Parameters

Die Size	5.467 mm x 2.053 mm
Die Thickness	0.265 mm
Passivation	Polyimide
Top side metal	See figures 1, 2 and 3
Bottom side metal	See figures 1, 2 and 3

Electrical Characteristics at Wafer Level

(Typical values at $T_J = 25\text{ }^\circ\text{C}$, $V_{GS} = 6\text{ V}$ unless otherwise noted)

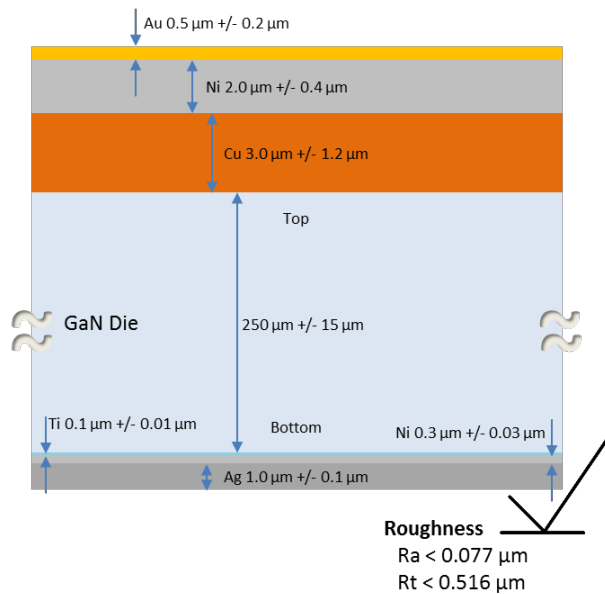
Parameter	Sym.	Min.	Typ.	Max.	Unit	Conditions
Drain-to-Source Blocking Voltage	BV_{DS}	100			V	$V_{GS}=0\text{ V}$, $I_{DSS} \leq 50\text{ }\mu\text{A}$
Drain-to-Source On Resistance (note 3)	$R_{DS(on)}$		7	9.5	m Ω	$V_{GS} = 6\text{ V}$, $T_J = 25\text{ }^\circ\text{C}$, $I_{DS} = 9.0\text{ A}$
Gate Threshold Turn on Voltage	$V_{GS(th)}$	1.1	1.3	2.5	V	$V_{DS} = V_{GS}$, $I_D = 7\text{ mA}$
Drain to Source Leakage Current	I_{DSS}		0.5	50	μA	$V_{DS} = 100\text{ V}$, $V_{GS} = 0\text{ V}$
Gate to Source Current	I_{GSS}		200		μA	$V_{GS} = 6\text{ V}$, $V_{DS} = 0\text{ V}$
Internal Gate Resistance	R_G		0.64		Ω	$f=1\text{ MHz}$, open drain
Input Capacitance	C_{ISS}		588		pF	$V_{DS} = 80\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1\text{ MHz}$
Output Capacitance	C_{OSS}		254		pF	
Reverse Transfer Capacitance	C_{RSS}		9.9		pF	
Total Gate Charge	Q_G		12		nC	$V_{GS} = 0\text{ to }6\text{ V}$ $V_{DS} = 50\text{ V}$ $I_D = 90\text{ A}$
Gate-to-Source Charge	Q_{GS}		4.5		nC	
Gate-to-Drain Charge	Q_{GD}		1.5		nC	
Output Charge	Q_{OSS}		35		nC	$V_{GS} = 0\text{ V}$, $V_{DS} = 50\text{ V}$
Reverse Recovery Charge	Q_{RR}		0		nC	

(3) Die is not tested to full current in production. Please refer to GS61008P data sheet for more detailed characteristics

Ordering Information

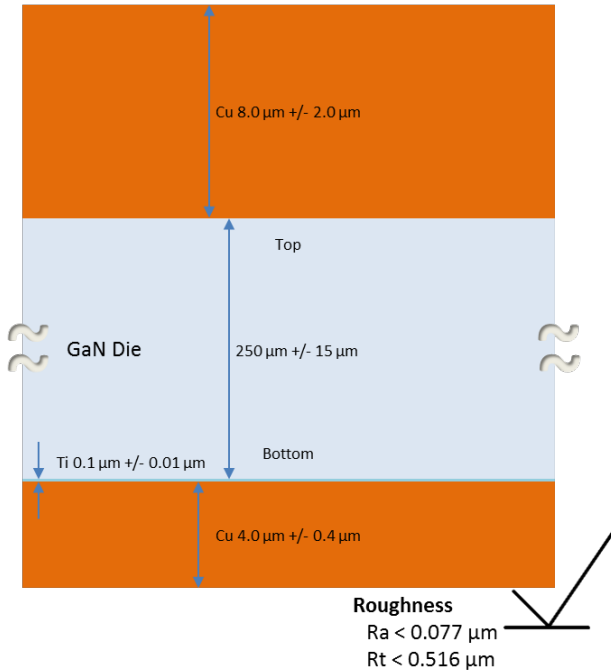
Part number	Die Finish	Packing Method
TDG100E90D1	Option 1: NiAu/Ag	Contact Factory
TDG100E90D2	Option 2: Cu/Cu	Contact Factory
TEG100E90D3	Option 3: Cu/Ag	Contact Factory

Die Finish Options



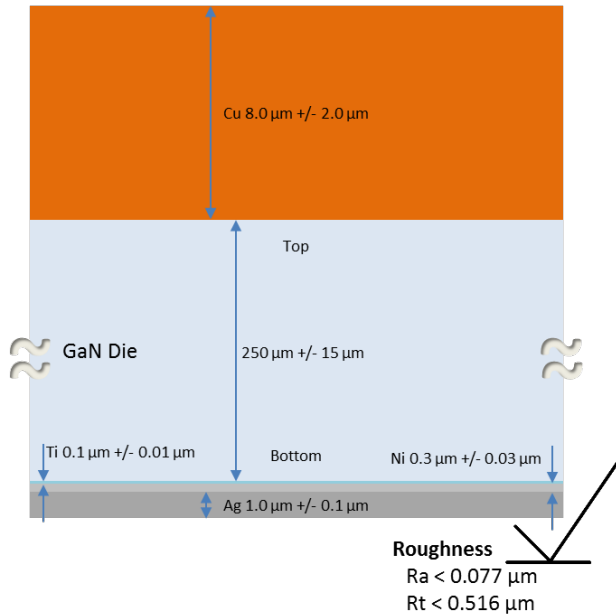
Material	Thickness	Comment
Au	0.5 μm +/- 0.2 μm	Die top side = gold finish
Ni	2.0 μm +/- 0.4 μm	
Cu	3.0 μm +/- 1.2 μm	
GaN	250 μm +/- 15 μm	Die Core
Ti	0.1 μm +/- 0.01 μm	Die bottom side = silver finish
Ni	0.3 μm +/- 0.03 μm	
Ag	1.0 μm +/- 0.1 μm	

Figure 1: TDG100E90AD1X Ni/Au/Ag Die Finish



Material	Thickness	Comment
Cu	8.0 μm +/- 2.0 μm	Die top side = copper finish
GaN	250 μm +/- 15 μm	Die Core
Ti	0.1 μm +/- 0.01 μm	Die bottom side = copper finish
Cu	4.0 μm +/- 0.4 μm	

Figure 2: TDG100E90AD2X Cu/Cu Die Finish

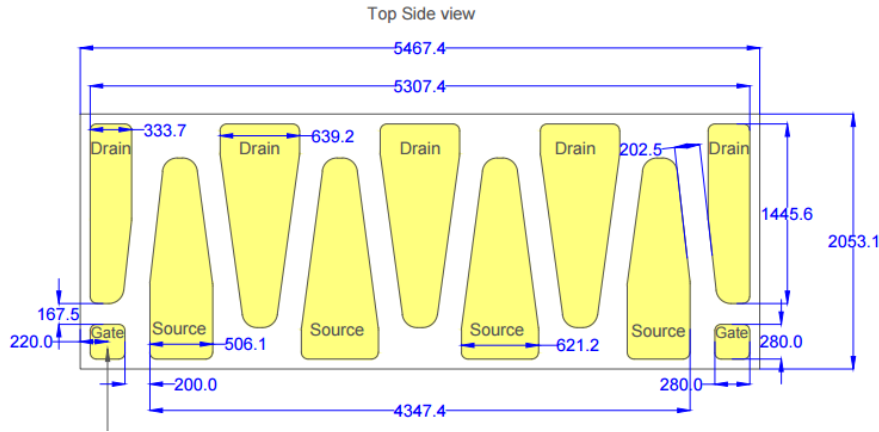


Material	Thickness	Comment
Cu	8.0 μm +/- 2.0 μm	Die top side = copper finish
GaN	250 μm +/- 15 μm	Die Core
Ti	0.1 μm +/- 0.01 μm	Die bottom side = silver finish
Ni	0.3 μm +/- 0.03 μm	
Ag	1.0 μm +/- 0.1 μm	

Figure 3: TDG100E90AD3X Cu/Ag Die Finish



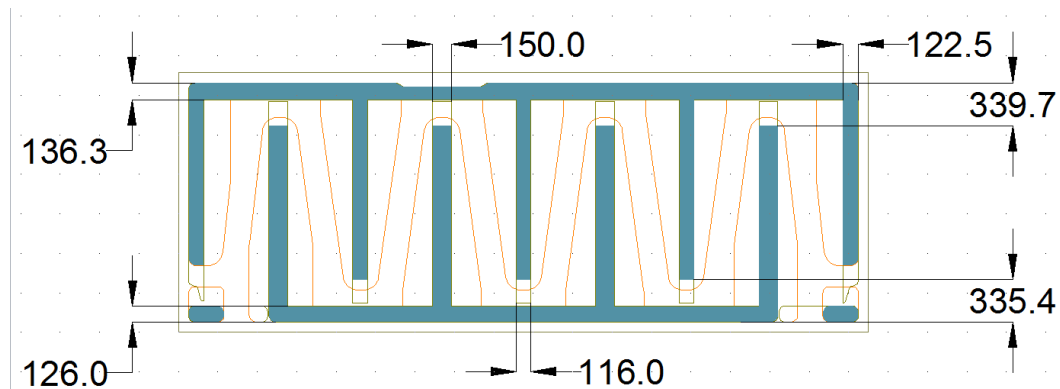
Dimensions



Dimension Drawing Notes:

1. All dimensions are in μm .
2. The drawing shows view of die facing up, substrate down.
3. The total die thickness is $265 \mu\text{m}$.

Figure 4: Die Top View



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